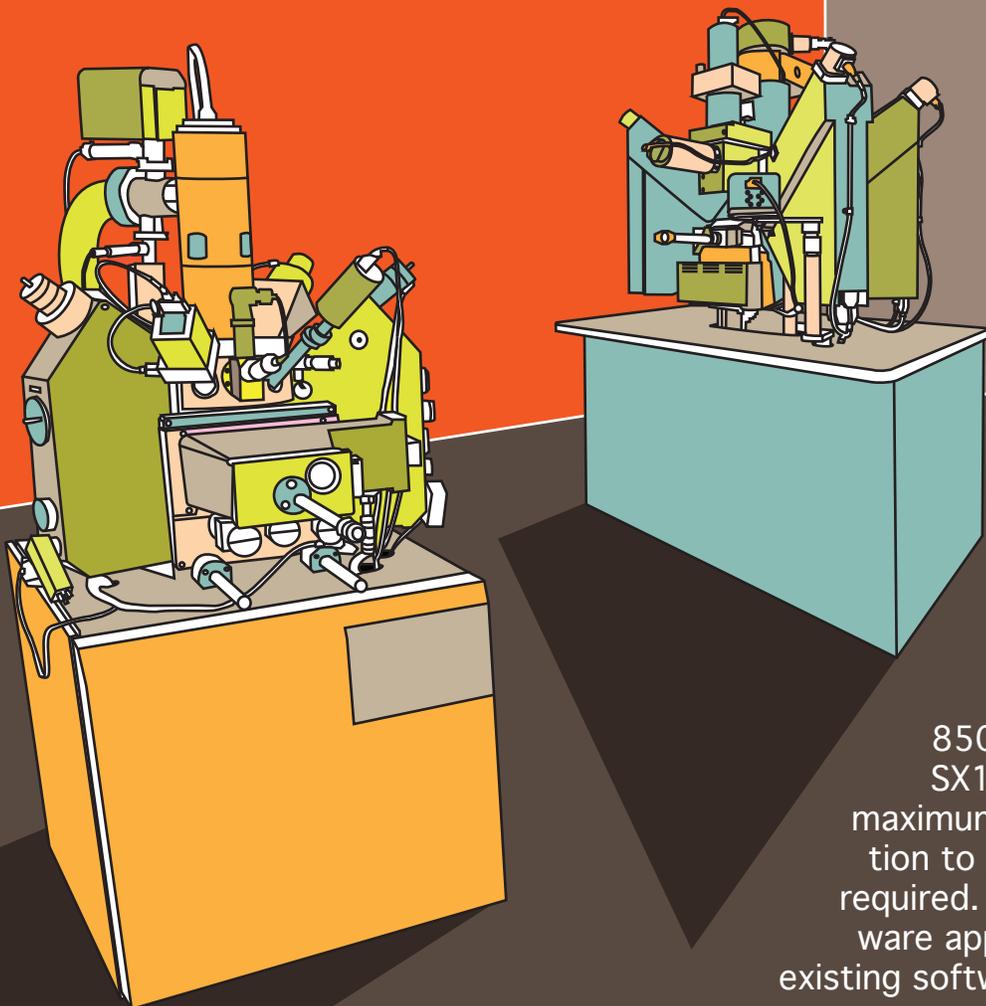


Probe Software

Microprobe Software
Designed by Users
For Users

Join our community of scientists and engineers who enjoy the most powerful and comprehensive automation and analysis tool for EPMA on the market today.



Probe Software utilizes a robust TCP/IP implementation for direct instrument communication to interface simultaneously alongside your existing JEOL 8900, 8200, 8500, 8230, 8530 and Cameca SX100 instrument computer for maximum compatibility. No modification to your current configuration is required. This means that Probe Software applications will work with your existing software to improve productivity and expand your options.

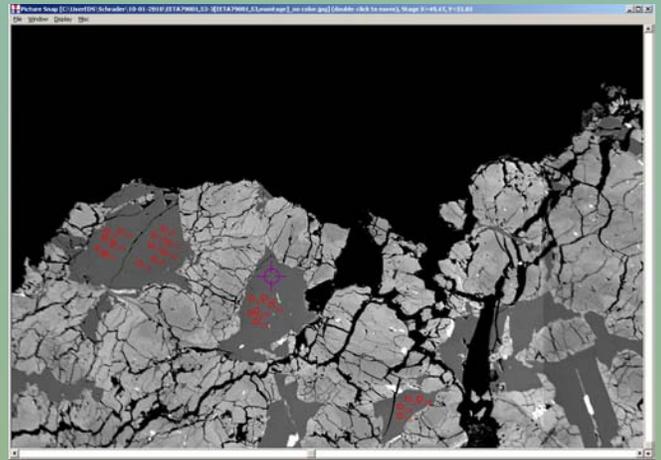
Probe Software

Probe for EPMA is the unparalleled choice for electron probe micro-analysis and here are a few reasons why:

Easy to Use

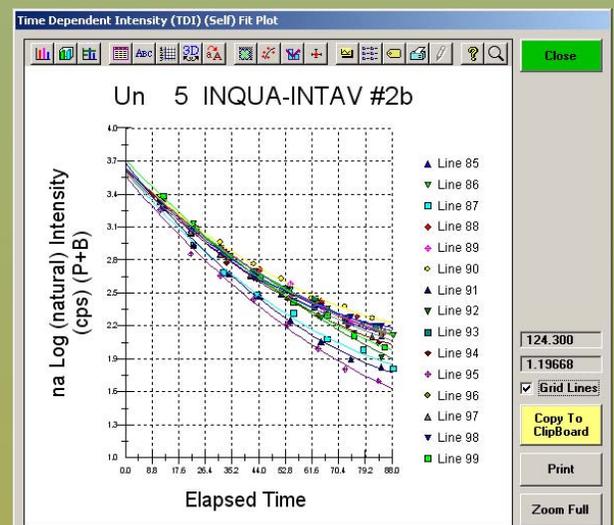
- Automatic saving of all intensity data and analytical parameters including instrument conditions, peaking scans, PHA scans, standards, unknowns, wavescans, digitized coordinates, images and EDS spectra. There is no “save button” to forget!
- Unlimited site license allows Probe for EPMA to be copied to off-line computers for data reprocessing. Every user gets a copy of the software with their data and updates are always free!
- Context sensitive on-line help including pop-up help on every control. Over 600 pages of detailed instructions including “Quick Start”, “Getting Started”, “Advanced Topics” and numerous application specific technical white papers.
- Multiple methods for saving and re-calling previous samples, settings, conditions, intensities, in addition to acquisition, calculation and output options for quick setup and re-use.

- Picture Snap sample navigator with live stage cursor for displaying sample coordinates along with scale bar, labels, etc. directly on your scanned, acquired or imported images. Digitize acquisition coordinates using the mouse and confirm them easily and quickly for final stage position and focus.

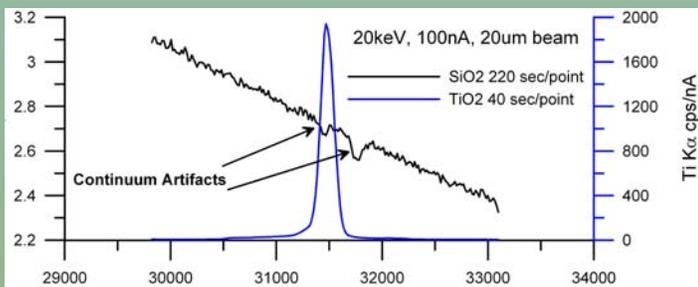


Accurate

- TryZAF correction algorithms and an expanded set of mass absorption coefficients in addition to empirically determined coefficients from the literature.
- Quantitative matrix iterated Spectral Interference correction for both major and trace element analysis, even for extreme overlap situations.
- Time Dependent Intensity (TDI) correction for accurate treatment of glasses, carbonates, hydrous minerals and other beam sensitive materials. Handles even “hyper-exponential” intensity loss at high beam currents or focused beams for ultimate accuracy.



- Integrated compound area peak factor (APF) correction for accurate light element analysis. Perform oxygen analyses with typical EPMA accuracy.
- Quantitative matrix iterated Blank Correction for ultra trace element accuracy. Essential for sub 100 PPM levels or when utilizing more than one spectrometer per element for aggregating element intensities for improved precision.



Time Saving

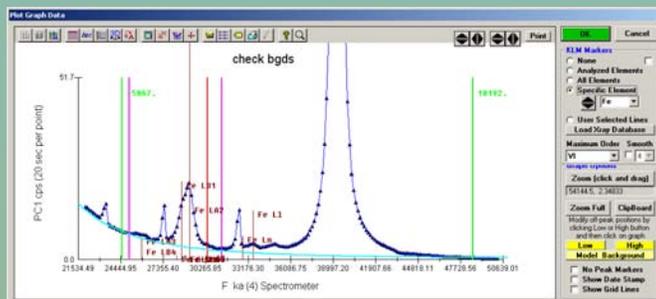
- Automated iterated polynomial fit Mean Atomic Number (MAN) background correction for major and minor element analysis. Improved accuracy for many situations by not having off-peak interferences.
- Standard database offers centralized entry, maintenance and evaluation of complex geological and materials standards. Indispensable for organizing standards, searching compositions and identifying potential matrix correction issues.

- Integrated EDS/WDS acquisition and analysis with storage of complete EDS spectrum and detector analysis parameters. Currently supports Thermo NSS and Bruker Esprit for spectrum and image acquisition.

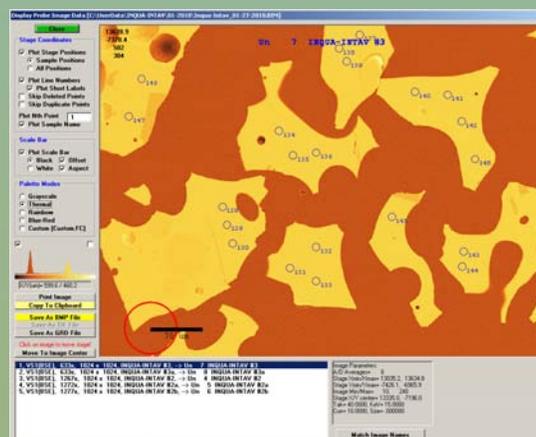
Flexible

- Write your own device independent VBA scripts for customized acquisition and analysis using our COM components with Excel, Matlab, Surfer or any OLE compliant application. Example scripts are provided for spectrometer reproducibility, deadtime calibration, etc. Run your microprobe from Excel!

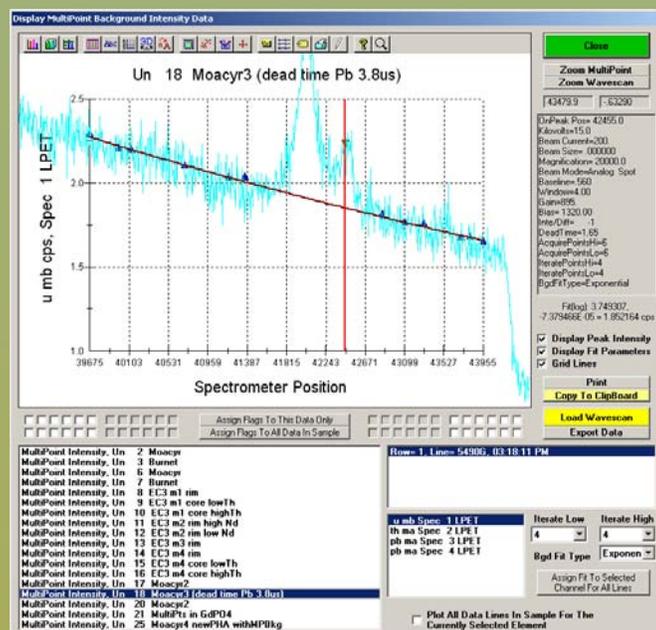
- Multiple (aggregate intensity) spectrometer measurement and extensive graphical background modeling options for improved trace element analysis.

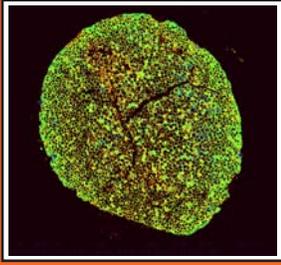


- Integrated imaging for BSE, SE and CL with automated display of analyzed positions, scale bar, annotation and aspect ratio control.



- Multi-point background feature acquires multiple off-peak intensities allowing the background to be more accurately characterized by automatically removing problematic background measurements using best fit statistical evaluation methods.





Probe Image Electron Microprobe Imaging and Mapping Software

- Acquire simultaneous analog signal or x-ray pulse count images of any size (limited only by available memory). Wide area stage scanning of unlimited size and shape with automatic mosaic feature.
- Real time histogram and real world coordinate display for data cursor and statistics. Absolute XY image registration in stage coordinates.
- Complete image automation of multiple fields of view and multiple elements (on and off peak) with automatic Z stage interpolation for multiple acquisition fields.
- Options for multiple point quantitative calibration curves or background, spectral interference and matrix corrected quantitative imaging of x-ray intensities.
- Phase analysis with 2d histogram for phase discrimination. Live cursor, XY scale bar, single or continuous image acquisition. Extensive image processing capabilities.

No other package offers the capabilities, flexibility, accuracy, ease of use, and time saving advantages. Probe for EPMA and Probe Image are the total solution for every analytical challenge.

 **Probe Software**

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